



**Computing Platform Service Partner**

# **GENE-1350**

## **Temperature/Humidity Test Report**

**Report NO: 10E020031**

**Issued by: Rex Chang / 09/28/2010**  
\_\_\_\_\_  
**Test Engineer Date**

**Reviewed by: Jansin Lee / 09/28/2010**  
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**Sr. Manager Date**

# Test item list

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## Testing Result

Num	Test item list	Result	Remark
1	Temp./humidity power on/off test	Pass	
2	Temperature variation operation test	Pass	
3	Cold start and hot start test	Pass	

# Configuration of EUT

## Test Product: GENE-1350 A0.3

### Sample Configuration & Quantity Under Test:

1. CPU: TI OMAP 3530
2. Chipset: TI OMAP 3530
3. VGA: TI OMAP 3530
4. Memory: Onboard 256MB LP DDR RAM / Micron 9TA17 D9JWW
5. Flash : Onboard 2GB / Micron MT29F2G16ABD NAND Flash
6. Test Software: Windows CE 6.0 / Run one Microsoft media player simultaneously
7. Power Adapter: Chi CH-1024

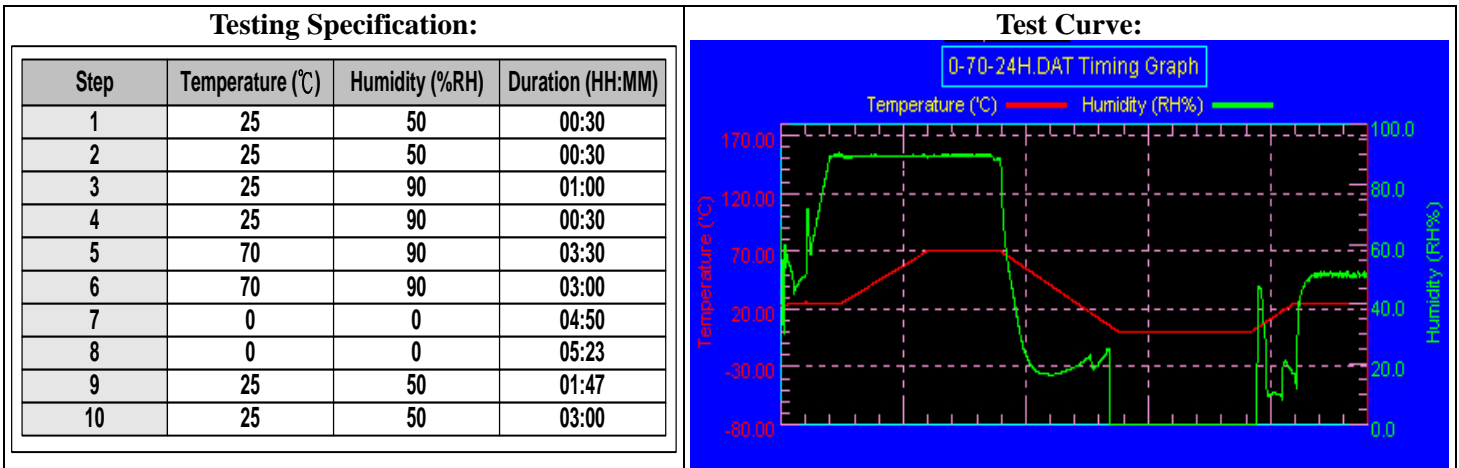
**Test Date:** 09-27~28-2010

**Test Site:** AAEON QE Internal Lab.

**Test Standard:** Reference IEC 68-2-30 Testing procedures  
Test Db: Damp Heat Test

**Test Equipment:**  
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-D4H+-100  
Date of Calibration: 11/12/09  
Serial Number: 2582

**Temperature & Humidity Power On/Off Test:**



**Test Result:**

No problem was found during the temperature & humidity power on/off test.

Test Method	Actual	Successful	Failure rate
Power On/Off	1926/times	1926/times	0 %
Note: Failure rate need to under 0.2%.			

**Test Date:** 09-24~25-2010

**Test Site:** AAEON QE Internal Lab.

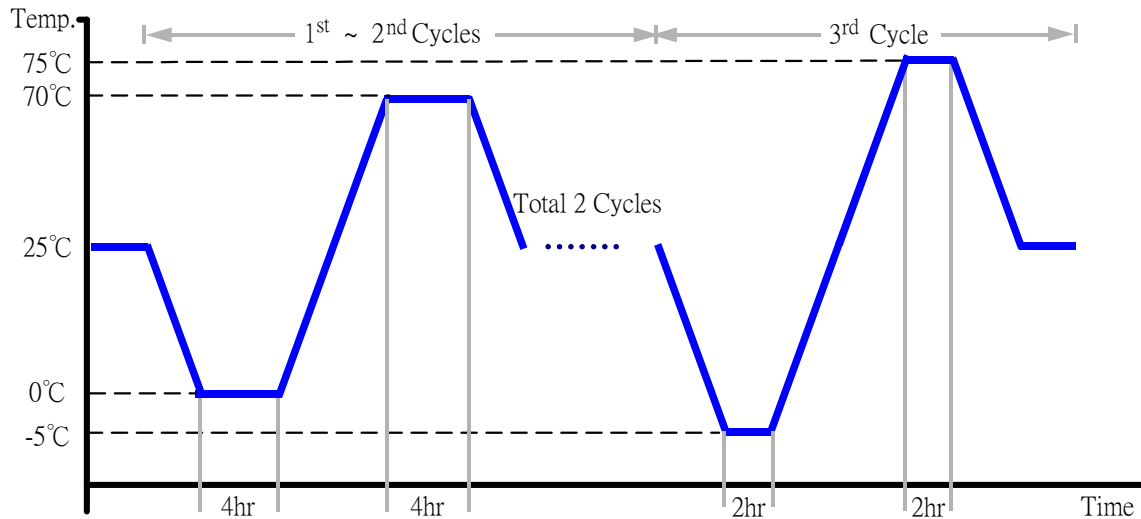
**Test Standard:** Reference IEC 68-2-14 Testing procedures  
Test N: Change of temperature Test

**Test Equipment:**

Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-D4H+-100  
Date of Calibration: 11/12/09  
Serial Number: 2582

**Temperature & Humidity Cycle Test:**

1. Test Low Temperature: 0°C (1~2 cycles)  
-5°C (3<sup>rd</sup> cycle)
2. Test High Temperature: 70°C (1~2 cycles)  
75°C (3<sup>rd</sup> cycle)
3. Test dwell time: 4Hrs (1~2 cycles)  
2Hrs (3<sup>rd</sup> cycle)
4. Temperature slope: 2°C/min
5. Test cycle: 3 cycles
6. Test Environment Curve:



**Test Result:**

No problem was found during the temperature variation operation test.

# Cold start and hot start test

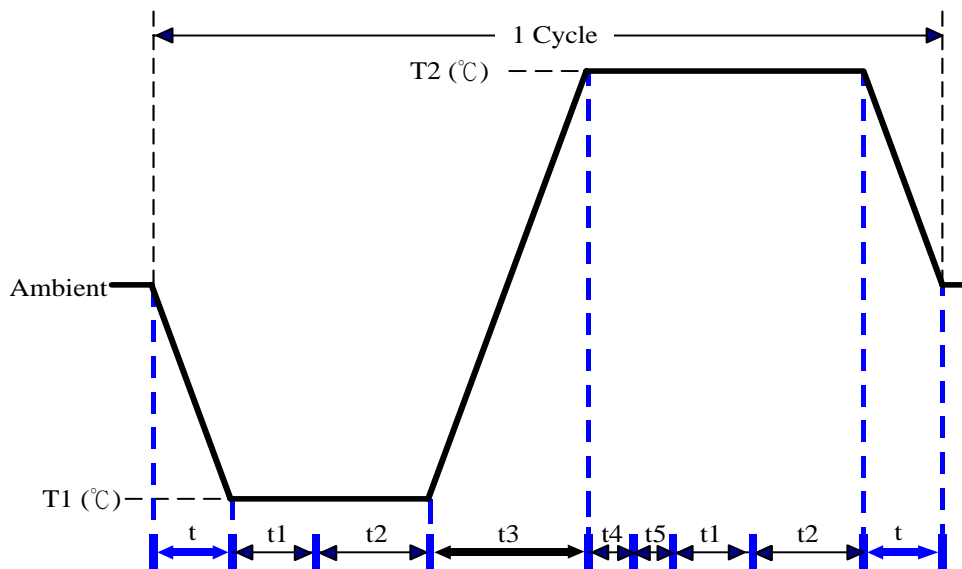
**Test Date:** 09-23~24-2010

**Test Site:** AAEON QE Internal Lab.

**Test Standard:** Reference IEC 68-2-14 Testing procedures  
Test N: Change of temperature Test

**Test Equipment:**  
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-D4H+-100  
Date of Calibration: 11/12/09  
Serial Number: 2582

**Test Condition:**



Parameters	Description
T1	-5°C
T2	75°C
t1	1 hrs
t2	2 hrs
t4, t5	30 min
t, t3	2°C/min
n (Cycle)	1

t,t3 = temprature slope  
t, t1: Power Off  
t2: Power on/off test 10 times (on 2 min / off 5min)  
t3,t4: Run one Microsoft media player simultaneously  
t5: Win CE power on/off test 2 times  
Test Software:Windows CE

**Test Result:**

- a. No problem was found during the cold start test.
- b. No problem was found during the hot start test.